



Appl. No. 09/742,224

#9/B
6/4/03
Hayes

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 09/742,224
Applicant : Walx FANG ET AL
Filed : December 22, 2000
Title : METHOD FOR DETERMINING FAILURE RATE
: AND SELECTING BEST BURN-IN TIME
TC/A.U. : 2857
Examiner : Baran, Mary C
Docket No. : 4425-102

Honorable Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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MAY 29 2003
TECHNOLOGY CENTER 2800

AMENDMENT

Sir:

In response to the Official Action mailed February 27, 2003. Applicants respectfully request that the Examiner reconsider the amended application according to the following remarks.

Please amend the above-identified application as follows:

In the Specification:

Please replace the paragraph beginning at page 7, line 10, with the following rewritten paragraph:

As life-time testing block 22 shows, performs a life-time testing process to establish a failure rate testing time relation by measuring the